


<b>Search Notes</b>  	<b>Application/Control No.</b>  10527546	<b>Applicant(s)/Patent Under Reexamination</b>  CHEDELLA ET AL.
	<b>Examiner</b>  RICHARD CHAN	<b>Art Unit</b>  2618

SEARCHED			
Class	Subclass	Date	Examiner
455	564, 563, 556,	8/24/08	RC
375	355	8/24/08	RC

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner